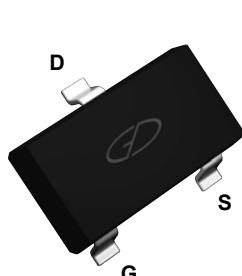
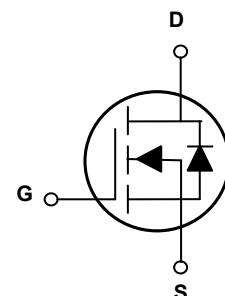


### Main Product Characteristics

$V_{DSS}$	60V
$R_{DS(ON)}$	70m $\Omega$ (typ.)
$I_D$	2.7A



SOT-23



Schematic Diagram

### Features and Benefits

- Advanced MOSFET process technology
- Ideal for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



### Description

The SSF6092G1 utilizes the latest trench processing techniques to achieve high cell density, low on-resistance and high repetitive avalanche rating. These features make this device extremely efficient and reliable for use in power switching applications and a wide variety of other applications.

### Absolute Maximum Ratings ( $T_C=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Max.	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous, $V_{GS} @ 10\text{V}^1$	$I_D$	2.7	A
Drain Current-Pulsed <sup>2</sup>	$I_{DM}$	10.8	A
Power Dissipation <sup>3</sup>	$P_D$	1.25	W
Linear Derating Factor		0.01	W/ $^\circ\text{C}$
Junction-to-Ambient ( $t \leq 10\text{s}$ ) <sup>4</sup>	$R_{\theta JA}$	99	$^\circ\text{C/W}$
Junction-to-Ambient (PCB mounted, steady-state) <sup>4</sup>		100	$^\circ\text{C/W}$
Operating Junction Temperature Range	$T_J$	-55 To +150	$^\circ\text{C}$
Storage Temperature Range	$T_{STG}$	-55 To +150	$^\circ\text{C}$

**Electrical Characteristics** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	60	-	-	V
Drain-Source Leakage Current	$\text{I}_{\text{DSS}}$	$\text{V}_{\text{DS}}=60\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
Gate-Source Leakage Current	$\text{I}_{\text{GSS}}$	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
Gate Threshold Voltage	$\text{V}_{\text{GS(th)}}$	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}, \text{I}_D=250\mu\text{A}$	1.0	-	2.5	V
Static Drain-Source On-Resistance	$\text{R}_{\text{DS(ON)}}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=2.7\text{A}$	-	70	92	$\text{m}\Omega$
<b>Dynamic and Switching Characteristics</b>						
Total Gate Charge	$\text{Q}_g$	$\text{V}_{\text{DD}}=40\text{V}, \text{I}_D=4\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$	-	12	-	nC
Gate-Source Charge	$\text{Q}_{\text{gs}}$		-	3.5	-	
Gate-Drain Charge	$\text{Q}_{\text{gd}}$		-	3.7	-	
Turn-On Delay Time	$\text{t}_{\text{d(on)}}$	$\text{V}_{\text{DS}}=25\text{V}, \text{R}_{\text{GEN}}=50\Omega$ $\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=1.2\text{A}$	-	9.2	-	nS
Rise Time	$\text{t}_r$		-	16.7	-	
Turn-Off Delay Time	$\text{t}_{\text{d(off)}}$		-	35.4	-	
Fall Time	$\text{t}_f$		-	8.6	-	
Input Capacitance	$\text{C}_{\text{iss}}$	$\text{V}_{\text{DS}}=25\text{V}, \text{V}_{\text{GS}}=0\text{V},$ $\text{F}=1\text{MHz}$	-	641	-	pF
Output Capacitance	$\text{C}_{\text{oss}}$		-	48	-	
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$		-	38	-	
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Continuous Source Current (Body Diode) <sup>1</sup>	$\text{I}_s$	MOSFET symbol showing the integral reverse p-n junction diode.	-	-	2.7	A
Pulsed Source Current (Body Diode)	$\text{I}_{\text{sM}}$		-	-	10.8	A
Diode Forward Voltage	$\text{V}_{\text{SD}}$	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=2.7\text{A}, \text{T}_j=25^\circ\text{C}$	-	0.85	1.3	V

**Notes:**

- ① Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ .

## Test Circuits and Waveforms

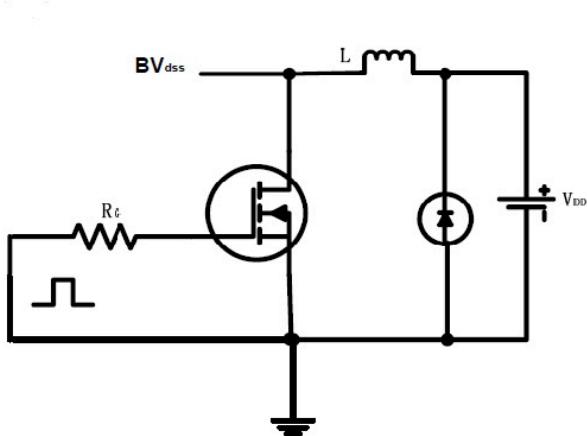


Figure 1. EAS Test Circuit:

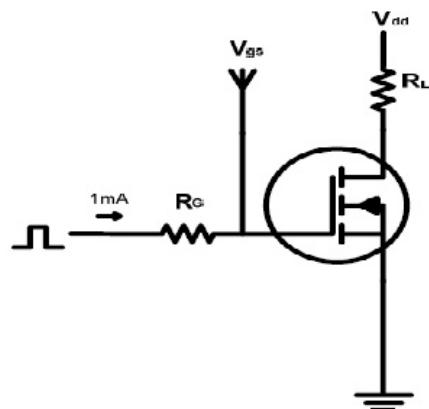


Figure 2. Gate Charge Test Circuit:

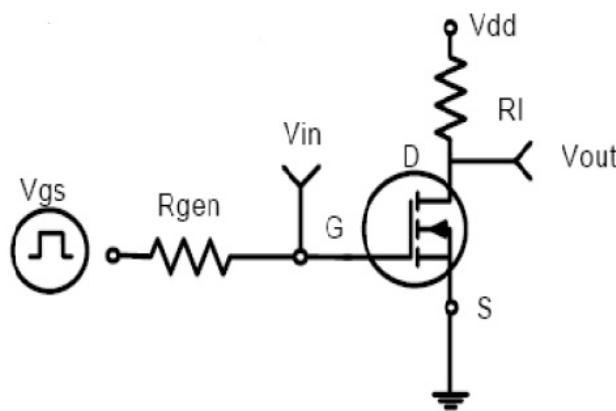


Figure 3. Switching Time Test Circuit:

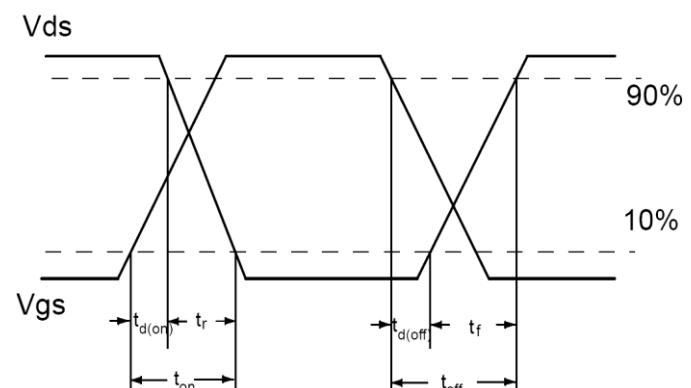


Figure 4. Switch Waveforms:

## Thermal Characteristics

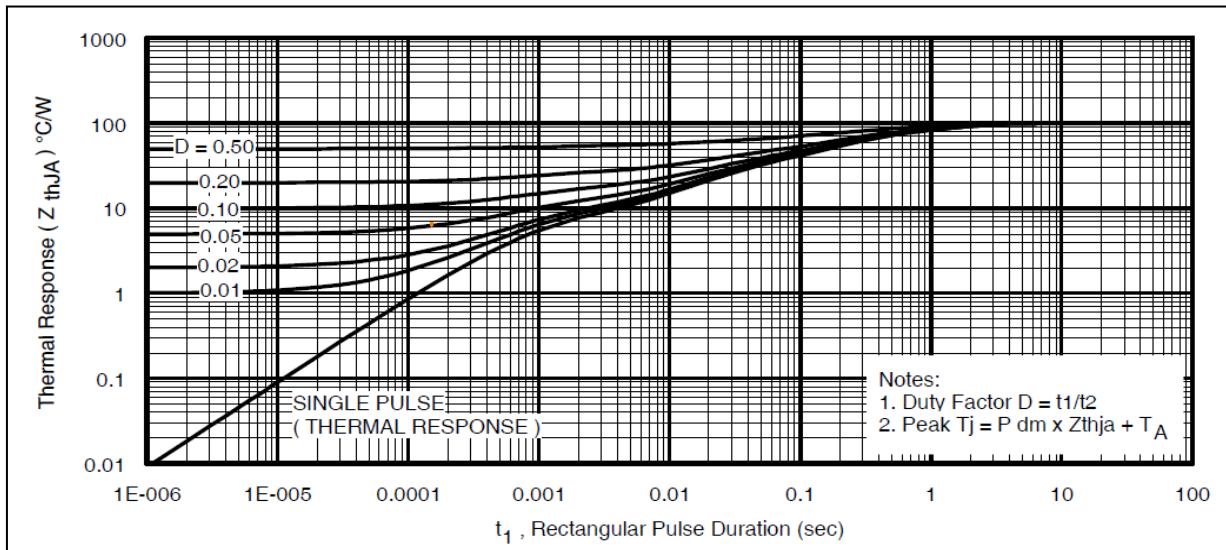
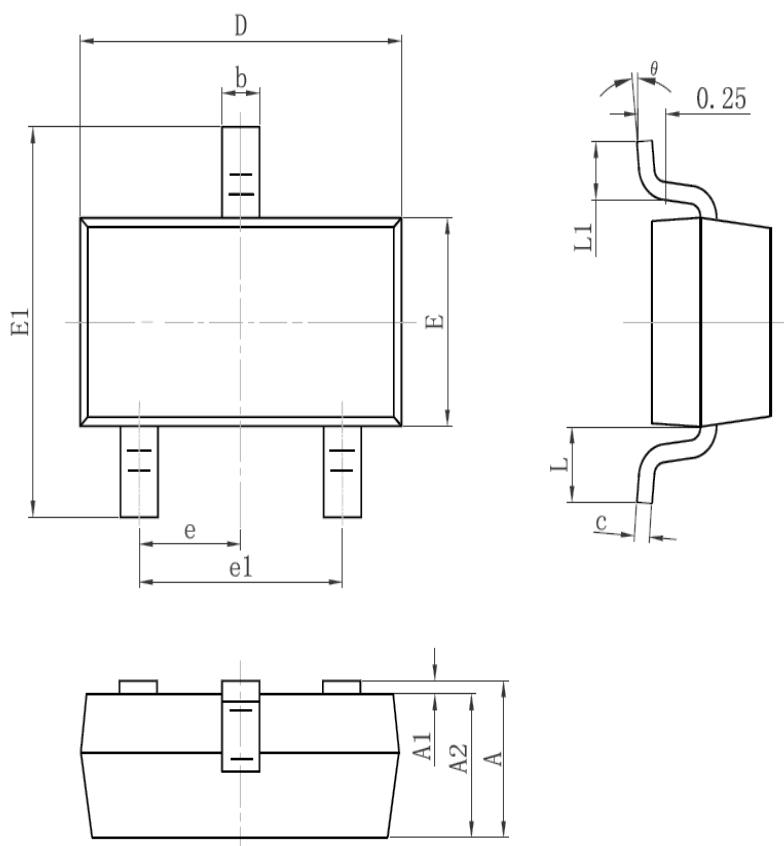


Figure 5. Typical Effective Transient Thermal Impedance, Junction-to-Ambient

### Package Outline Dimensions (SOT-23)



Symbol	Dimension In Millimeters		Dimension In Inches	
	Min	Max	Min	Max
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.95TYP		0.037TYP	
e1	1.800	2.000	0.071	0.079
L	0.55REF		0.022REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°